Substitute for Form 1449 A & R/PTO			Complete if Known			
Substitute for Porm 1449 A & B/P I G				Application Number	10/572,957	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT			HDE	Confirmation Number	4788	
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STATEMENT BY APPLICANT		ANI	First Named Inventor	Toshiaki KAKINAMI		
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				Examiner Name	Unkown	
Sheet	1	of	1	Attorney Docket Number	O92639	

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Examiner	Cite	Document N	Document Number					
Initials*	No.1	Number	(if known)	Publication Date MM-DD-YYYY		Name of Patentee or Applicant of Cited Document		
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Examiner Signature	Date Considered

*EXAMINER; Initial if reference considered, whether or not citation is in conformance with MFEP 609. Down line through citation if not in conformance and not considered. Include copy of this form with next consumeration to applicant.

*Applicant's using oftenion designation neether (optional). See Case Case of Case Of Deptil D